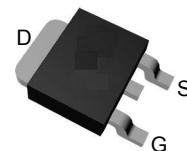


P-Channel Enhancement Mode MOSFET**Pin Configuration**

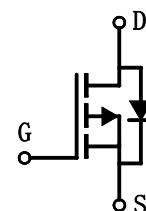
- -30V/-70A
- $R_{DS(ON)}=5.1\text{m}\Omega$ (typ) @ $V_{GS}=-20\text{V}$
 $R_{DS(ON)}=6.2\text{m}\Omega$ (typ) @ $V_{GS}=-10\text{V}$
- 100% UIS & RG Tested
- Reliable and Rugged
- Lead Free and Green Devices Available
(RoHS Compliant)



Top View of TO-252-3

Applications

- Power Management for Industrial DC/DC Converters

**Absolute Maximum Ratings** ($T_A = 25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Rating	Unit
Common Ratings			
V_{DSS}	Drain-Source Voltage	-30	V
V_{GSS}	Gate-Source Voltage	± 25	
I_D	Continuous Drain Current ^G	$T_c=25^\circ\text{C}$	A
		$T_c=100^\circ\text{C}$	
I_{DM}	Pulsed Drain Current ^C	$T_c=25^\circ\text{C}$	A
I_{DSM}	Continuous Drain Current	$T_A=25^\circ\text{C}$	
		$T_A=70^\circ\text{C}$	
P_D	Power Dissipation ^B	$T_c=25^\circ\text{C}$	W
		$T_c=100^\circ\text{C}$	
T_{STG}, T_j	Storage Temperature Range	-55 to 175	°C
P_{DSM}	Power Dissipation ^A	$T_A=25^\circ\text{C}$	W
		$T_A=70^\circ\text{C}$	
I_{AS}	Single pulsed avalanche Current ^C	-50	A
E_{AS}	Single pulsed avalanche energy ^C	$L=0.1\text{mH}$	mJ
$R_{\theta JC}$	Thermal Resistance-Junction to Case	Steady-State	°C/W
$R_{\theta JA}$	Thermal Resistance-Junction to Ambient ^{AD}	$t \leq 10\text{s}$	
		Steady-State	

Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D=-250\mu\text{A}, V_{GS}=0\text{V}$	-30			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=-30\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$			-1 -5	μA
I_{GSS}	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}= \pm 25\text{V}$			± 100	nA
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=-250\mu\text{A}$	-1.5	-2.5	-3.5	V
$I_{\text{D(ON)}}$	On state drain current	$V_{GS}=-10\text{V}, V_{DS}=-5\text{V}$	-200			A
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance	$V_{GS}=-20\text{V}, I_D=-20\text{A}$ $T_J=125^\circ\text{C}$		5.1 7.6	6.2 9.2	$\text{m}\Omega$
		$V_{GS}=-10\text{V}, I_D=-20\text{A}$		6.2	8	$\text{m}\Omega$
g_{FS}	Forward Transconductance	$V_{DS}=-5\text{V}, I_D=-20\text{A}$	42			S
V_{SD}	Diode Forward Voltage	$I_S=-1\text{A}, V_{GS}=0\text{V}$		-0.7	-1	V
I_S	Maximum Body-Diode Continuous Current ^G				-70	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=-15\text{V}, f=1\text{MHz}$	2310	2890	3500	pF
C_{oss}	Output Capacitance		410	585	760	pF
C_{rss}	Reverse Transfer Capacitance		280	470	660	pF
R_g	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$	1.9	3.8	5.7	Ω
SWITCHING PARAMETERS						
Q_g	Total Gate Charge	$V_{GS}=-10\text{V}, V_{DS}=-15\text{V}, I_D=-20\text{A}$	40	51	61	nC
Q_{gs}	Gate Source Charge		10	12	14	nC
Q_{gd}	Gate Drain Charge		10	16	22	nC
$t_{\text{D(on)}}$	Turn-On DelayTime	$V_{GS}=-10\text{V}, V_{DS}=-15\text{V}, R_L=0.75\Omega, R_{\text{GEN}}=3\Omega$		16		ns
t_r	Turn-On Rise Time			12		ns
$t_{\text{D(off)}}$	Turn-Off DelayTime			45		ns
t_f	Turn-Off Fall Time			22		ns
t_{rr}	Body Diode Reverse Recovery Time	$I_F=-20\text{A}, dI/dt=100\text{A}/\mu\text{s}$	14	18	22	ns
Q_{rr}	Body Diode Reverse Recovery Charge	$I_F=-20\text{A}, dI/dt=100\text{A}/\mu\text{s}$	9	11	13	nC

A. The value of $R_{\theta JA}$ is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{ C}$. The Power dissipation P_{DSM} is based on $R_{\theta JA}$ and the maximum allowed junction temperature of 150° C . The value in any given application depends on the user's specific board design, and the maximum temperature of 175° C may be used if the PCB allows it.

B. The power dissipation P_D is based on $T_{J(\text{MAX})}=175^\circ\text{ C}$, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C. Repetitive rating, pulse width limited by junction temperature $T_{J(\text{MAX})}=175^\circ\text{ C}$. Ratings are based on low frequency and duty cycles to keep initial $T_J=25^\circ\text{ C}$.

D. The $R_{\theta JA}$ is the sum of the thermal impedance from junction to case $R_{\theta JC}$ and case to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using <300 μs pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of $T_{J(\text{MAX})}=175^\circ\text{ C}$. The SOA curve provides a single pulse rating.

G. The maximum current rating is package limited.

H. These tests are performed with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{ C}$.

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

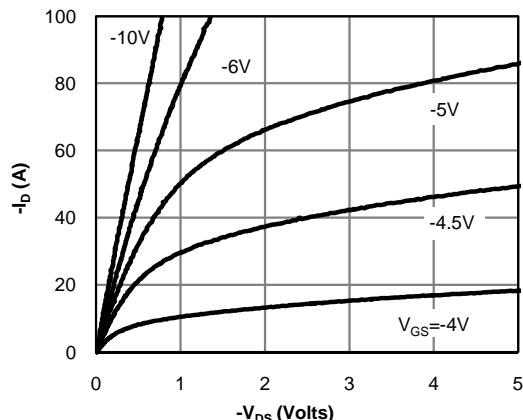


Fig 1: On-Region Characteristics (Note E)

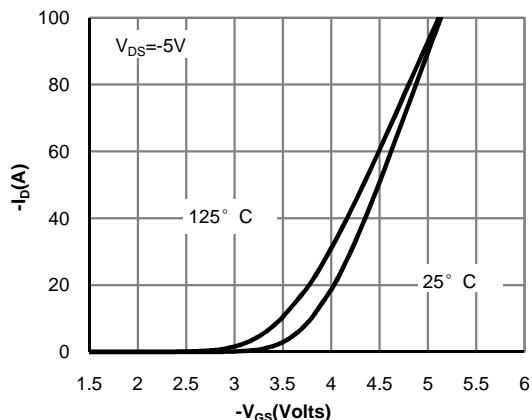


Figure 2: Transfer Characteristics (Note E)

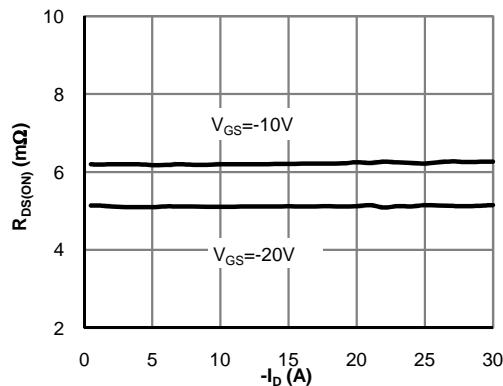


Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

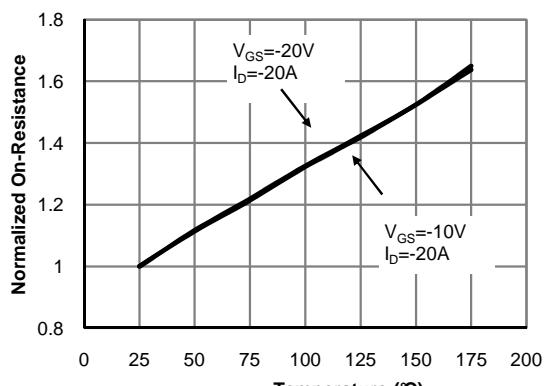


Figure 4: On-Resistance vs. Junction Temperature (Note E)

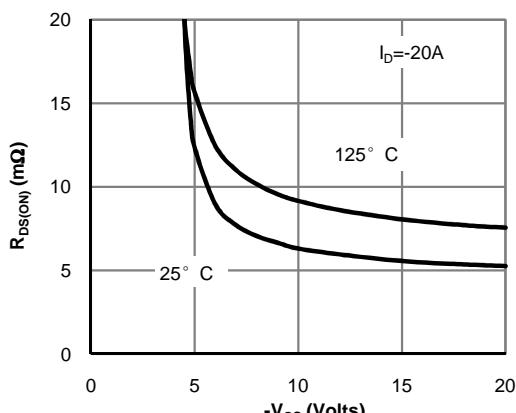


Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

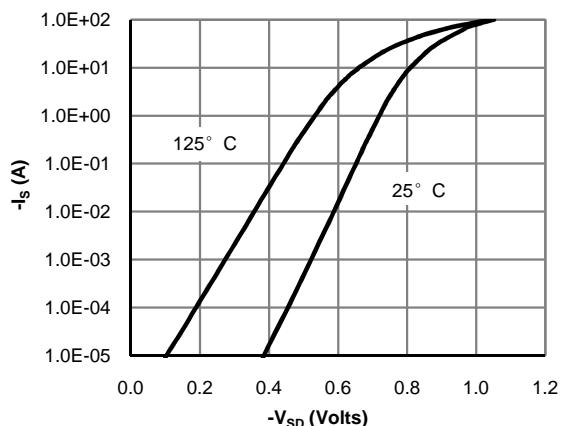


Figure 6: Body-Diode Characteristics (Note E)

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

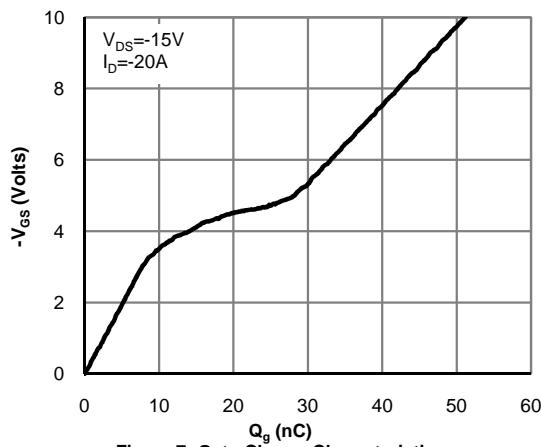


Figure 7: Gate-Charge Characteristics

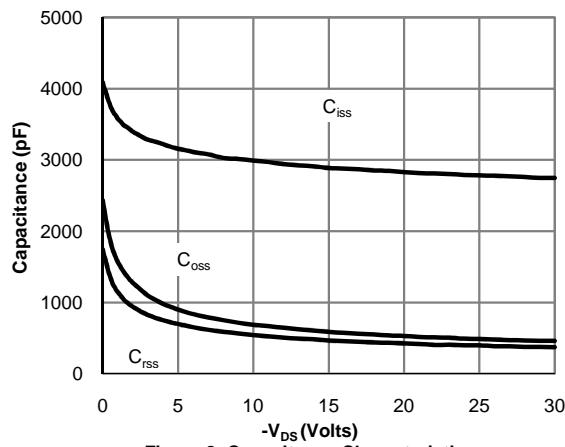


Figure 8: Capacitance Characteristics

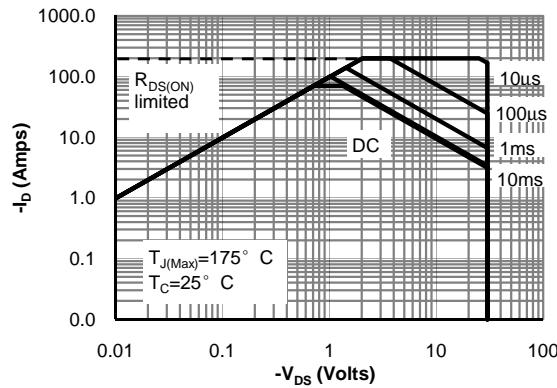


Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

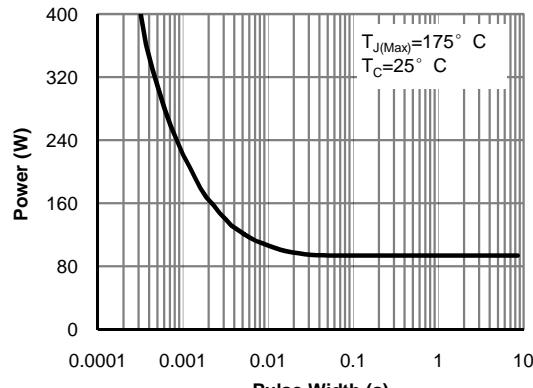


Figure 10: Single Pulse Power Rating Junction-to-Case (Note F)

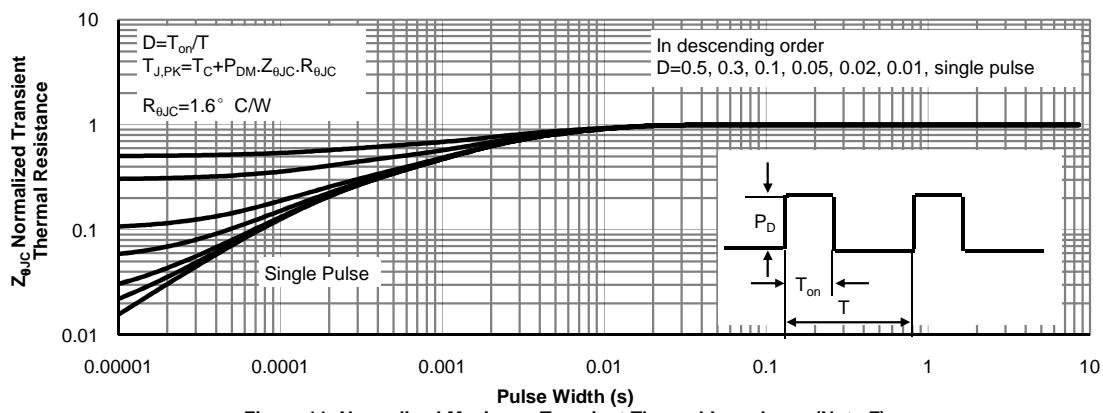
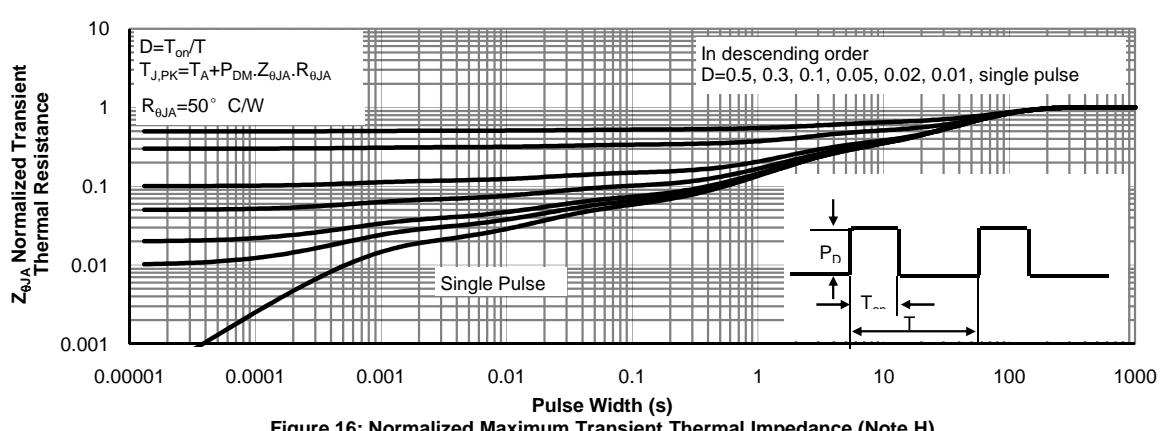
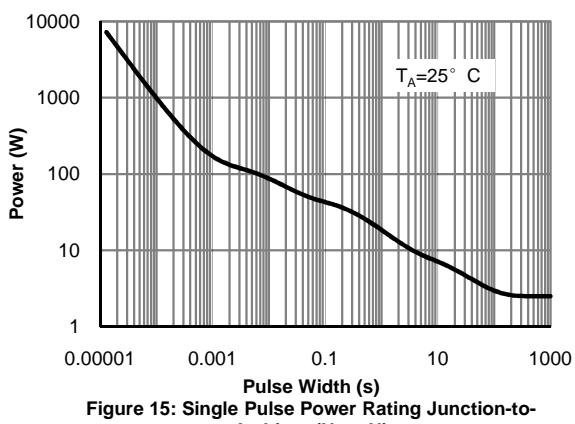
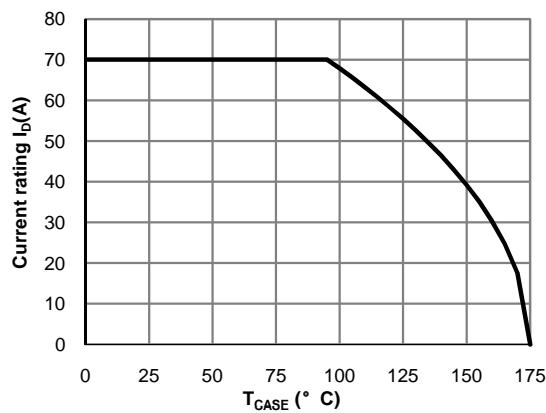
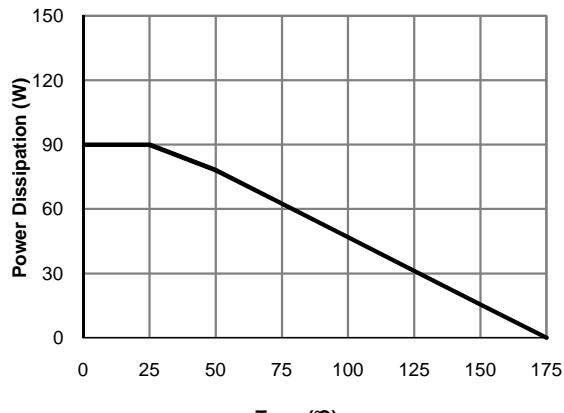
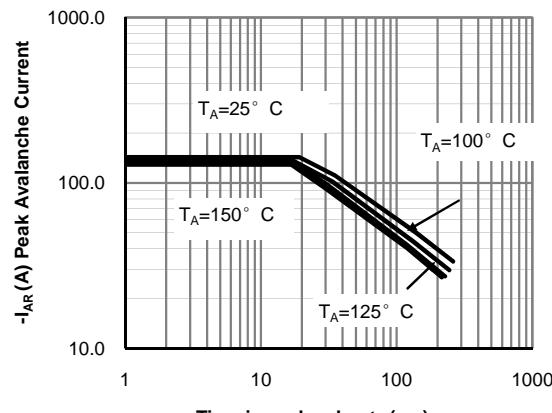
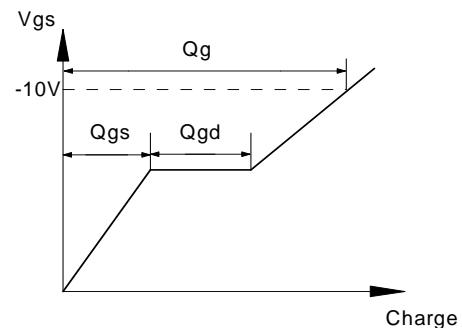
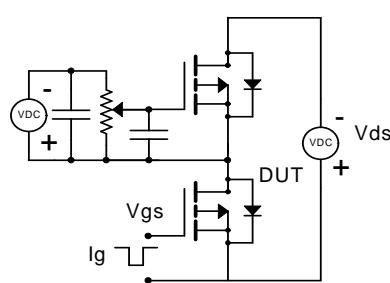


Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

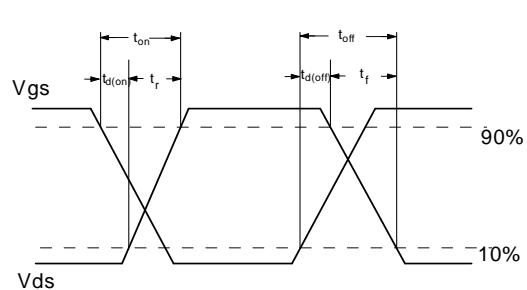
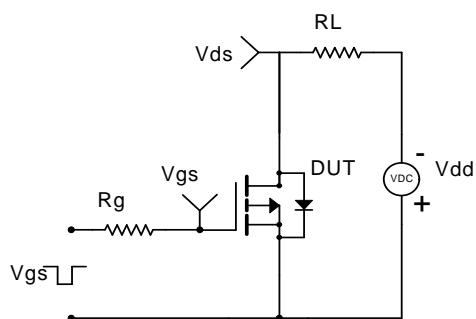
TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS



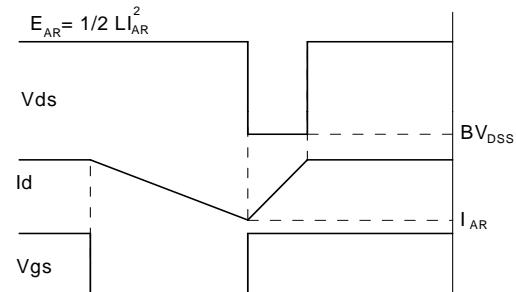
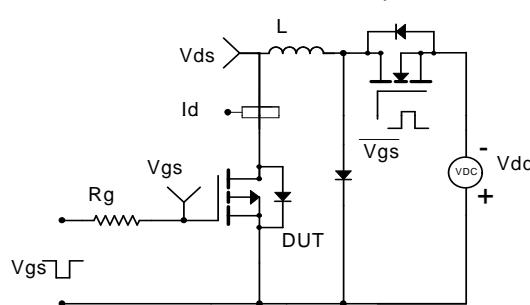
Gate Charge Test Circuit & Waveform



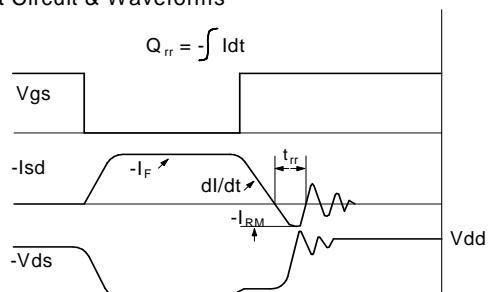
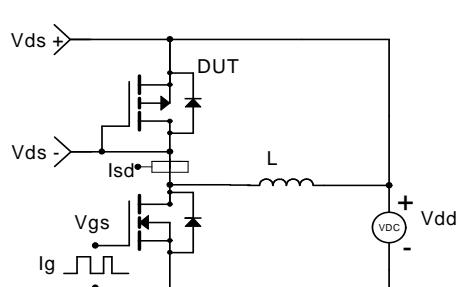
Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

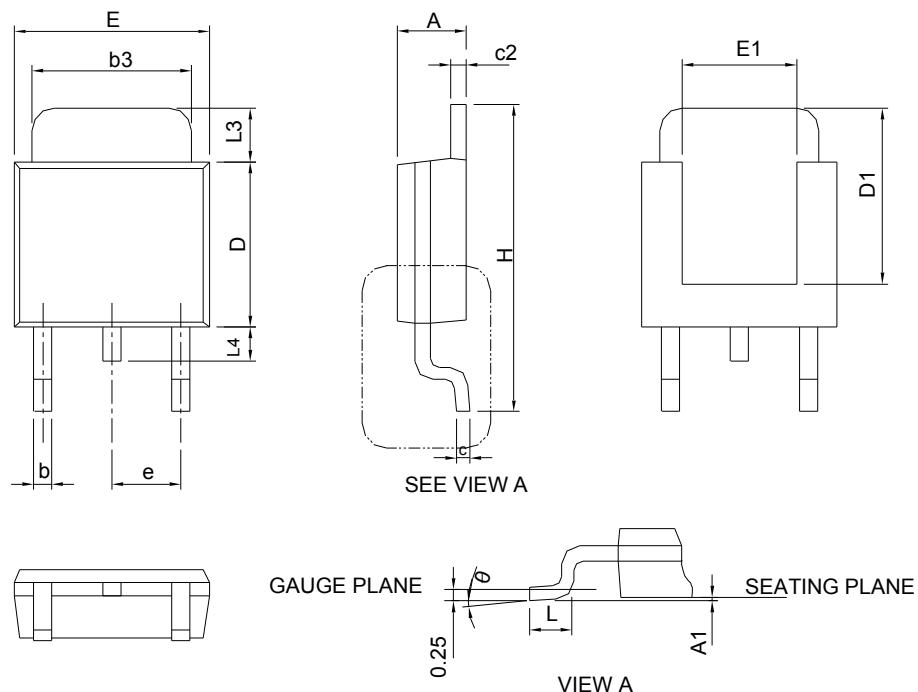


Diode Recovery Test Circuit & Waveforms



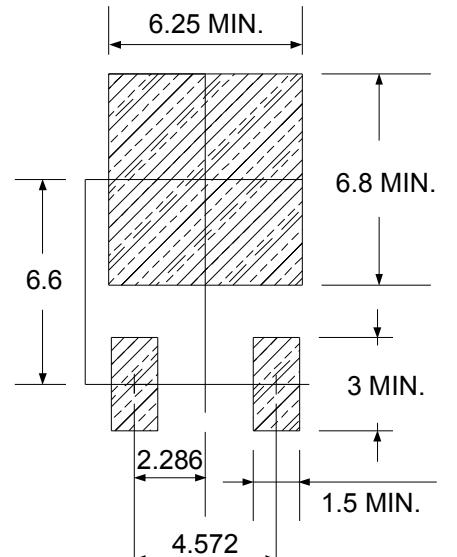
Package Information

TO-252-3



SYMBOL	TO-252-3			
	MILLIMETERS		INCHES	
	MIN.	MAX.	MIN.	MAX.
A	2.18	2.39	0.086	0.094
A1	-	0.13	-	0.005
b	0.50	0.89	0.020	0.035
b3	4.95	5.46	0.195	0.215
c	0.46	0.61	0.018	0.024
c2	0.46	0.89	0.018	0.035
D	5.33	6.22	0.210	0.245
D1	4.57	6.00	0.180	0.236
E	6.35	6.73	0.250	0.265
E1	3.81	6.00	0.150	0.236
e	2.29 BSC		0.090 BSC	
H	9.40	10.41	0.370	0.410
L	0.90	1.78	0.035	0.070
L3	0.89	2.03	0.035	0.080
L4	-	1.02	-	0.040
θ	0°	8°	0°	8°

RECOMMENDED LAND PATTERN



UNIT: mm

Note : Follow JEDEC TO-252 .